Application/Control No. Applicant(s)/Patent Under Reexamination 10/686,357 **FUNAKAWA ET AL.** Notice of References Cited Examiner Art Unit Page 1 of 1 1742 Deborah Yee **U.S. PATENT DOCUMENTS** Date **Document Number** Name Classification Country Code-Number-Kind Code MM-YYYY US-Α US-В С US-D US-Ε US-F US-US-G US-Н USı J US-Κ US-US-L US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY 406322479 11-1994 Japan Takashashi et al C22C 38/00 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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